

	Type	Hits	Search Text	DBs	Time Stamp	Comments	Error Definition
1	BRS	2	(gui or (grpahical adj1 user adj1 interface)) with testing with ((ingegrated adj1 circuit\$1) or ic\$1 or semiconductor or wafer)	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/06/17 09:56		
2	BRS	1	"6308322".PN.	USPAT	2003/06/16 08:36		
3	BRS	1	"6308320".PN.	USPAT	2003/06/16 08:37		
4	BRS	1	"6125460".PN.	USPAT	2003/06/16 08:37		
5	BRS	1	"5828985".PN.	USPAT	2003/06/16 08:37		
6	BRS	1	"5434805".PN.	USPAT	2003/06/16 08:38		
7	BRS	1	"5555417".PN.	USPAT	2003/06/16 08:38		
8	BRS	1	"5828985".PN.	USPAT	2003/06/16 08:38		
9	BRS	1	"5951704".PN.	USPAT	2003/06/16 08:38		
10	BRS	1	"6125460".PN.	USPAT	2003/06/16 08:38		
11	BRS	1	"6308320".PN.	USPAT	2003/06/16 08:39		
12	BRS	1	"5434805".PN.	USPAT	2003/06/16 08:40		
13	BRS	1	"5555417".PN.	USPAT	2003/06/16 08:41		

	Type	Hits	Search Text	DBs	Time Stamp	Comments	Error Definition
14	BRS	0	6484116.uref.	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/06/16 08:41		
15	BRS	8	(gui or (grpahical adj1 user adj1 interface)) with test\$3 with ((ingegrated adj1 circuit\$1) or ic\$1 or semiconductor or wafer)	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/06/16 08:45		
16	BRS	96	(gui or (grpahical adj1 user adj1 interface)) with ((ingegrated adj1 circuit\$1) or ic\$1 or semiconductor or wafer)	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/06/16 09:24		
17	BRS	1	(gui or (grpahical adj1 user adj1 interface)) with ((ingegrated adj1 circuit\$1) or ic\$1 or semiconductor or wafer) and matrix adj switch	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/06/16 08:53		
18	BRS	4926	matrix adj1 switch\$3	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/06/16 08:58		
19	BRS	3	(gui or (grpahical adj1 user adj1 interface)) with matrix adj1 switch\$3	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/06/16 10:26		

	Type	Hits	Search Text	DBs	Time Stamp	Comments	Error Definition
20	BRS	1	(gui or (grpahical adj1 user adj1 interface)) with ((ingegrated adj1 circuit\$1) or ic\$1 or semiconductor or wafer) and matrix adj1 switch\$3	USPAT; US-PGPUB; EPO; 2003/06/16 JPO; DERWENT; 08:58 IBM_TDB	2003/06/16 08:58		
21	BRS	38	(702/\$.cccls.) and matrix adj1 switch\$3	USPAT; US-PGPUB; EPO; 2003/06/16 JPO; DERWENT; 08:59 IBM_TDB	2003/06/16 08:59		
22	BRS	0	(gui or (grpahical adj1 user adj1 interface)) with ((ingegrated adj1 circuit\$1) or ic\$1 or semiconductor or wafer) with probe\$1 with pad\$1	USPAT; US-PGPUB; EPO; 2003/06/16 JPO; DERWENT; 09:24 IBM_TDB	2003/06/16 09:24		
23	BRS	1	(gui or (grpahical adj1 user adj1 interface)) and ((ingegrated adj1 circuit\$1) or ic\$1 or semiconductor or wafer) with probe\$1 with pad\$1	USPAT; US-PGPUB; EPO; 2003/06/16 JPO; DERWENT; 09:26 IBM_TDB	2003/06/16 09:26		
24	BRS	1	(gui or (grpahical adj1 user adj1 interface)) and ((ingegrated adj1 circuit\$1) or ic\$1 or semiconductor or wafer) and probe\$1 with card with pad\$1	USPAT; US-PGPUB; EPO; 2003/06/16 JPO; DERWENT; 09:26 IBM_TDB	2003/06/16 09:26		

Type	Hits	Search Text	DBs	Time Stamp	Comments	Error Definition
25 BRS	137	(gui or (grpahical adj1 user adj1 interface)) and test\$3 with ((ingegrated adj1 circuit\$1) or ic\$1 or semiconductor or wafer)	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/06/16 09:27		
26 BRS	146	(gui or (grpahical adj1 user adj1 interface)) and test\$3 with ((ingegrated adj1 circuit\$1) or ic\$1 or semiconductor\$1 or wafer\$1)	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/06/16 09:45		
27 BRS	2	(gui or (grpahical adj1 user adj1 interface)) and test\$3 with ((ingegrated adj1 circuit\$1) or ic\$1 or semiconductor\$1 or wafer\$1) and probe with card	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/06/16 09:31		
28 IS&R	2	("5726920").PN.	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/06/16 09:32		
29 BRS	19	5726920.uref.	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/06/16 09:41		

Type	Hits	Search Text	DBs	Time Stamp	Comments	Error Definition
30 IS&R	2	("5857192").PN.	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/06/16 09:41		
31 BRS	7	(gui or (grpahical adj1 user adj1 interface)) and test\$3 with ((ingegrated adj1 circuit\$1) or ic\$1 or semiconductor\$1 or wafer\$1) and (head\$2 or probe\$1) and pad\$1	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/06/16 09:59		
32 BRS	74	(gui or (grpahical adj1 user adj1 interface)) and test\$3 with ((ingegrated adj1 circuit\$1) or ic\$1 or semiconductor\$1 or wafer\$1) and (head\$2 or probe\$1)	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/06/16 10:26		
33 BRS	70	(gui or (grpahical adj1 user adj1 interface)) and test\$3 with ((ingegrated adj1 circuit\$1) or ic\$1 or semiconductor\$1 or wafer\$1) and (head\$2 or probe\$1) and (switch\$3 or select\$3)	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/06/16 14:28		

Type	Hits	Search Text	DBs	Time Stamp	Comments	Error Definition
34 BRS	14	(gui or (grpahical adj1 user adj1 interface)) with test\$3 and ((ingegrated adj1 circuit\$1) or ic\$1 or semiconductor\$1 or wafer\$1) and (head\$2 or probe\$1) with (switch\$3 or select\$3)	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/06/16 10:37		
35 BRS	2	(gui or (grpahical adj1 user adj1 interface)) and test\$3 with ((ingegrated adj1 circuit\$1) or ic\$1 or semiconductor\$1 or wafer\$1) with(head\$2 or probe\$1) with (switch\$3 or select\$3)	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/06/16 10:46		
36 BRS	13	(gui or (grpahical adj1 user adj1 interface)) and test\$3 with ((ingegrated adj1 circuit\$1) or ic\$1 or semiconductor\$1 or wafer\$1) with (switch\$3 or select\$3)	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/06/17 12:29		
37 BRS	6724	test\$3 with ((ingegrated adj1 circuit\$1) or ic\$1 or semiconductor\$1 or wafer\$1) with (switch\$3 or select\$3)	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/06/16 10:59		

Type	Hits	Search Text	DBs	Time Stamp	Comments	Error Definition
38 BRS	500	((ingegrated adj1 circuit\$1) or ic\$1 or semiconductor\$1 or wafer\$1) with test\$3 with (head\$3 or probe\$1) with (switch\$3 or select\$3)	USPAT; US-PGPUB; EPO; 2003/06/16 JPO; DERWENT; 11:07 IBM_TDB			
39 BRS	2	(gui or (grpahical adj user adj interface)) and ((ingegrated adj1 circuit\$1) or ic\$1 or semiconductor\$1 or wafer\$1) with test\$3 with (head\$3 or probe\$1) with (switch\$3 or select\$3)	USPAT; US-PGPUB; EPO; 2003/06/16 JPO; DERWENT; 11:05 IBM_TDB			
40 BRS	22	((ingegrated adj1 circuit\$1) or ic\$1 or semiconductor\$1 or wafer\$1) with test\$3 with (head\$3 or probe\$1) with matrix with (switch\$3 or select\$3)	USPAT; US-PGPUB; EPO; 2003/06/16 JPO; DERWENT; 11:09 IBM_TDB			
41 BRS	20	test\$3 with ((ingegrated adj1 circuit\$1) or ic\$1 or semiconductor\$1 or wafer\$1) and silicon with band with gap with voltage	USPAT; US-PGPUB; EPO; 2003/06/16 JPO; DERWENT; 16:41 IBM_TDB			
42 BRS	0	test\$3 with ((ingegrated adj1 circuit\$1) or ic\$1 or semiconductor\$1 or wafer\$1) with silicon with band with gap with voltage	USPAT; US-PGPUB; EPO; 2003/06/16 JPO; DERWENT; 14:36 IBM_TDB			

Type	Hits	Search Text	DBs	Time Stamp	Comments	Error Definition
43 BRS	0	test\$3 with ((ingegrated adj1 circuit\$1) or ic\$1 or semiconductor\$1 or wafer\$1) with silicon with band with gap with voltage with capacitance	USPAT; US-PGPUB; EPO; 2003/06/16 JPO; DERWENT; IBM_TDB	2003/06/16 14:37		
44 BRS	442	test\$3 with ((ingegrated adj1 circuit\$1) or ic\$1 or semiconductor\$1 or wafer\$1) with capacitance	USPAT; US-PGPUB; EPO; 2003/06/16 JPO; DERWENT; IBM_TDB	2003/06/16 16:03		
45 BRS	90	test\$3 with ((ingegrated adj1 circuit\$1) or ic\$1 or semiconductor\$1 or wafer\$1) and (select\$3 or switch\$3) with manual with automatic\$4	USPAT; US-PGPUB; EPO; 2003/06/16 JPO; DERWENT; IBM_TDB	2003/06/16 16:08		
46 BRS	112	test\$3 with ((ingegrated adj1 circuit\$1) or ic\$1 or semiconductor\$1 or wafer\$1) with measur\$3 with capacitance	USPAT; US-PGPUB; EPO; 2003/06/16 JPO; DERWENT; IBM_TDB	2003/06/16 16:26		
47 BRS	6	test\$3 with ((ingegrated adj1 circuit\$1) or ic\$1 or semiconductor\$1 or wafer\$1) with capacitance and (select\$3 or switch\$3) with manual with automatic\$4	USPAT; US-PGPUB; EPO; 2003/06/16 JPO; DERWENT; IBM_TDB	2003/06/16 16:10		

	Type	Hits	Search Text	DBs	Time Stamp	Comments	Error Definition
48	BRS	0	test\$3 with ((ingegrated adj1 circuit\$1) or ic\$1 or semiconductor\$1 or wafer\$1) with measur\$3 with capacitance and manual with automatic\$4	USPAT; US-PGPUB; EPO; 2003/06/16 JPO; DERWENT; IBM_TDB	2003/06/16 16:25		
49	BRS	13	test\$3 with ((ingegrated adj1 circuit\$1) or ic\$1 or semiconductor\$1 or wafer\$1) and silicon with band with gap with voltage and capacit\$4	USPAT; US-PGPUB; EPO; 2003/06/17 JPO; DERWENT; IBM_TDB	2003/06/17 13:50		
50	BRS	1	((ingegrated adj1 circuit\$1) or ic\$1 or semiconductor\$1 or wafer\$1) and (test\$3 or measur\$3) with silicon with band with gap with voltage and capacit\$4	USPAT; US-PGPUB; EPO; 2003/06/16 JPO; DERWENT; IBM_TDB	2003/06/16 16:33		
51	BRS	176	((ingegrated adj1 circuit\$1) or ic\$1 or semiconductor\$1 or wafer\$1) and silicon with band with gap with voltage and capacit\$4	USPAT; US-PGPUB; EPO; 2003/06/16 JPO; DERWENT; IBM_TDB	2003/06/16 16:34		
52	BRS	0	test\$3 with ((ingegrated adj1 circuit\$1) or ic\$1 or semiconductor\$1 or wafer\$1) and silicon with band with gap with voltage with capacit\$4	USPAT; US-PGPUB; EPO; 2003/06/16 JPO; DERWENT; IBM_TDB	2003/06/16 16:34		

	Type	Hits	Search Text	DBs	Time Stamp	Comments	Error Definition
53	BRS	89	((integrated adj1 circuit\$1) or ic\$1 or semiconductor\$1 or wafer\$1) with silicon with band with gap with voltage	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/06/16 16:48		
54	BRS	1	(gui or (grpahical adj1 user adj1 interface)) with ((integrated adj1 circuit\$1) or ic\$1 or semiconductor or wafer) and probe with card	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/06/17 09:58		
55	BRS	2	(gui or (grpahical adj1 user adj1 interface)) and ((integrated adj1 circuit\$1) or ic\$1 or semiconductor or wafer) with probe with card	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/06/17 10:00		
56	BRS	2	(gui or (grpahical adj1 user adj1 interface)) and ((integrated adj1 circuit\$1) or ic\$1 or semiconductor or wafer) and probe with card	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/06/17 10:01		
57	BRS	2	(gui or (grpahical adj1 user adj1 interface)) and ((integrated adj1 circuit\$1) or ic\$1 or semiconductor or wafer) and probe with card	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/06/17 10:01		

Type	Hits	Search Text	DBs	Time Stamp	Comments	Error Definition
58 BRS	3	(gui or (grpahical adj user adj interface)) and ((ingegrated adj1 circuit\$1) or ic\$1 or semiconductor\$1 or wafer\$) and probe\$1 with card\$1	USPAT; US-PGPUB; EPO; 2003/06/17 JPO; DERWENT; IBM_TDB	2003/06/17 10:07		
59 BRS	3	HP-4156B	USPAT; US-PGPUB; EPO; 2003/06/17 JPO; DERWENT; IBM_TDB	2003/06/17 12:32		
60 BRS	1	"Agilent 81110A"	USPAT; US-PGPUB; EPO; 2003/06/17 JPO; DERWENT; IBM_TDB	2003/06/17 12:29		
61 BRS	4	HP-4156B or hp adj1 4156b	USPAT; US-PGPUB; EPO; 2003/06/17 JPO; DERWENT; IBM_TDB	2003/06/17 12:33		
62 BRS	102	test\$3 with ((ingegrated adj1 circuit\$1) or ic\$1 or semiconductor\$1 or wafer\$1) and silicon with band with gap	USPAT; US-PGPUB; EPO; 2003/06/17 JPO; DERWENT; IBM_TDB	2003/06/17 14:00		
63 BRS	32	test\$3 with ((ingegrated adj1 circuit\$1) or ic\$1 or semiconductor\$1 or wafer\$1) and silicon with band with gap and capacitance	USPAT; US-PGPUB; EPO; 2003/06/17 JPO; DERWENT; IBM_TDB	2003/06/17 14:03		

	Type	Hits	Search Text	DBs	Time Stamp	Comments	Error Definition
64	BRS	0	test\$3 with ((ingegrated adj1 circuit\$1) or ic\$1 or semiconductor\$1 or wafer\$1) and silicon with band with gap with capacitance	USPAT; US-PGPUB; EPO; 2003/06/17 JPO; DERWENT; IBM_TDB	2003/06/17 13:52		
65	BRS	2	test\$3 with ((ingegrated adj1 circuit\$1) or ic\$1 or semiconductor\$1 or wafer\$1) and silicon with band with gap with capacit\$4	USPAT; US-PGPUB; EPO; 2003/06/17 JPO; DERWENT; IBM_TDB	2003/06/17 14:03		
66	BRS	3	test\$3 with ((ingegrated adj1 circuit\$1) or ic\$1 or semiconductor\$1 or wafer\$1) and measur\$3 with silicon with band with gap	USPAT; US-PGPUB; EPO; 2003/06/17 JPO; DERWENT; IBM_TDB	2003/06/17 14:02		
67	BRS	102	test\$3 with ((ingegrated adj1 circuit\$1) or ic\$1 or semiconductor\$1 or wafer\$1) and silicon with band with gap	USPAT; US-PGPUB; EPO; 2003/06/17 JPO; DERWENT; IBM_TDB	2003/06/17 14:04		
68	BRS	2	test\$3 with ((ingegrated adj1 circuit\$1) or ic\$1 or semiconductor\$1 or wafer\$1) with silicon with band with gap	USPAT; US-PGPUB; EPO; 2003/06/17 JPO; DERWENT; IBM_TDB	2003/06/17 14:13		
69	BRS	0	test\$3 with ((ingegrated adj1 circuit\$1) or ic\$1 or semiconductor\$1 or wafer\$1 or silicon) with band with gap with capacit\$4	USPAT; US-PGPUB; EPO; 2003/06/17 JPO; DERWENT; IBM_TDB	2003/06/17 14:17		

	Type	Hits	Search Text	DBs	Time Stamp	Comments	Error Definition
70	BRS	2	test\$3 with ((ingegrated adj1 circuit\$1) or ic\$1 or semiconductor\$1 or wafer\$1 or silicon) with band with gap same capacit\$4	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/06/17 14:20		
71	BRS	25	test\$3 with ((ingegrated adj1 circuit\$1) or ic\$1 or semiconductor\$1 or wafer\$1 or silicon) with band with gap	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/06/17 14:33		
72	BRS	7	test\$3 with ((ingegrated adj1 circuit\$1) or ic\$1 or semiconductor\$1 or wafer\$1 or silicon) with band with gap and capacit\$4	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/06/17 14:38		
73	BRS	2	"20020021141"	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/06/17 14:34		
74	BRS	3	test\$3 with ((ingegrated adj1 circuit\$1) or ic\$1 or semiconductor\$1 or wafer\$1 or silicon) with band with gap with voltage\$1	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/06/17 15:00		
75	BRS	251	test\$3 with ((ingegrated adj1 circuit\$1) or ic\$1 or semiconductor\$1 or wafer\$1 or silicon) with measur\$3 with capacit\$4	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/06/17 15:06		

Type	Hits	Search Text	DBs	Time Stamp	Comments	Error Definition
76 BRS	61	test\$3 with ((ingegrated adj1 circuit\$1) or ic\$1 or semiconductor\$1 or wafer\$1 or silicon) with measuring with capacitance	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/06/17 15:41		
77 BRS	6	5861882.uref.	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/06/17 15:45		
78 IS&R	2	("5861882").PN.	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/06/17 15:45		
79 BRS	2	"20030073894"	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/06/17 15:57		
80 BRS	2	"20020199142"	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/06/17 16:03		
81 BRS	602	702/68,81,82,83,84.ccls.	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/06/17 16:03		

	Type	Hits	Search Text	DBs	Time Stamp	Comments	Error Definition
82	BRS	1111	702/68,81,82,83,84,117.ccls.	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/06/17 16:04		
83	BRS	1868	702/68,81,82,83,84,117,118, 120,121,122,123,124.ccls.	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/06/17 16:08		
84	BRS	1195	324/73.1.ccls.	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/06/17 16:16		
85	BRS	4448	438/14,17.ccls.	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/06/17 16:16		
86	BRS	9235	324/73.1,538,548,754,755,7 56,759,761,765.ccls.	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/06/17 16:17		